In situ electric field transmission electron microscopy: Sample preparation & Experiment



TECHNISCHE UNIVERSITÄT DARMSTADT

A. Zintler¹, L. A. Schmitt¹, M. Zakhozheva¹, M. Acosta¹, W. Jo², U. Kunz¹, J. Rödel¹, H.-J. Kleebe¹

¹Institute of Materials- and Geo- Sciences, Technische Universität Darmstadt, Germany ²School of Materials Science and Engineering, Ulsan National Institute of Science and Technology, Ulsan 689-798, Republic of Korea

Introduction In situ transmission electron microscopy (TEM) of ferroelectric materials under an applied electric field allows insight in the processes that a material is undergoing on the microscopic scale. Performed sample preparation included standard processes like disc cutting, polishing and ion thinning. Subsequently, gold coated specimens were mounted into a modified in situ electric field TEM sample holder. With the chosen experimental setup electric fields perpendicular to the electron beam / viewing direction could be realized [1]. The microstructural evolution as a function of an applied electric field was studied in $Bi_{1/2}Na_{1/2}TiO_3$ -0.25SrTiO₃ core-shell piezoceramic [2].





Mechanical preparation

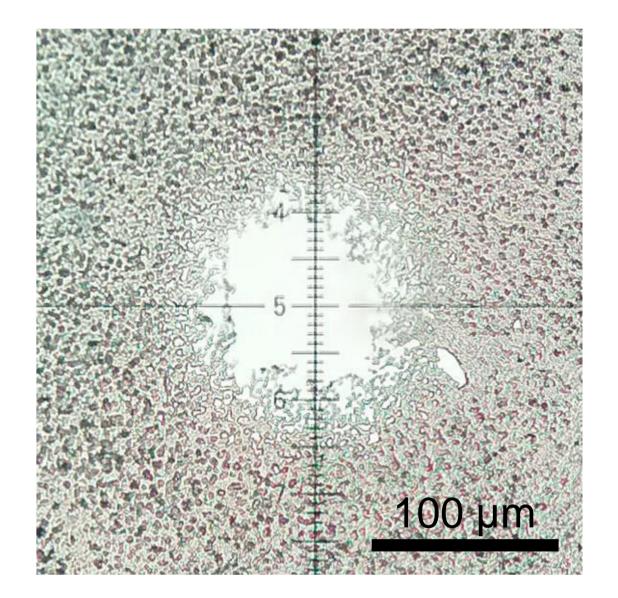
After cutting 3 mm diameter disks from the bulk material, the samples were mechanically ground down to a thickness of 120 μ m and polished on one side.

The other side was dimpled to retain planar surface for later one contacting. The dimple depth was adjusted to keep 20 μ m of material in order to minimize bending of the sample.

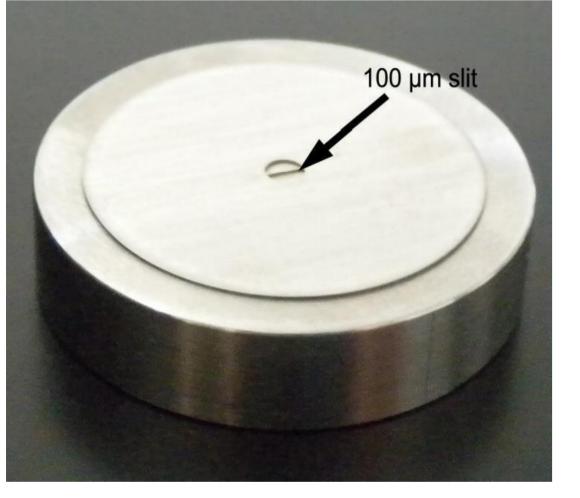
Ion thinning

Depending on their composition the specimens were annealed above Curie temperature in order to relieve stress induced mechanical by the preparation processes.

Argon ion thinning was applied until electron transparency and a hole opening of 100 μ m was reached.



older



Gold plating

Gold electrodes were evaporated on the even side of the sample. Therefore, coating masks with different slit widths, ranging between 100 μ m – 150 μ m, were designed. A parallel electrode geometry was achieved with the electric field oriented perpendicular to the propagation direction of the electron beam.

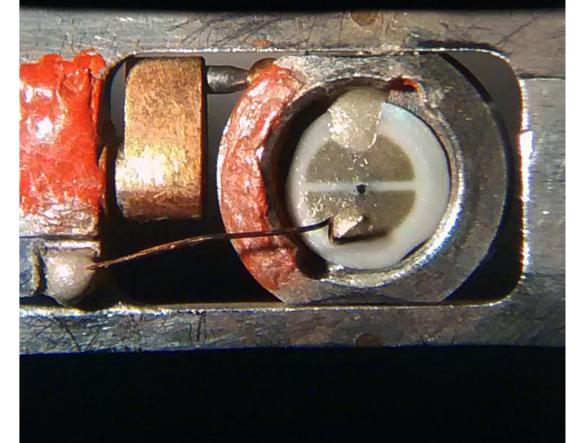
+4 kV/mm

Electrical wiring provided was through the rod to the tip of the *in situ* TEM specimen holder.

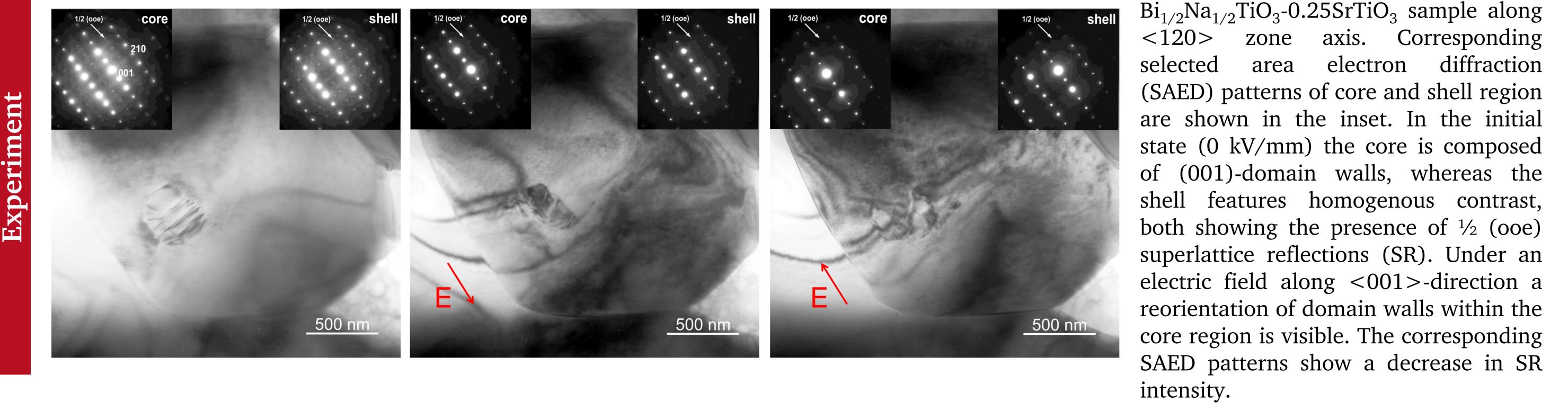
Contacting

The sample is mounted using an insulating varnish. The electrodes are then contacted with a copper or platinum wire to maintain β -tilting. Electric contacts were provided with the use of conductive epoxy glue.

-6 kV/mm



E = 0 kV/mm



Bright field imaging series of a Bi_{1/2}Na_{1/2}TiO₃-0.25SrTiO₃ sample along

Summary The shown TEM sample preparation technique and the *in situ* electric field characterization allows the observation of the impact of an electric field on various functional materials. In this study, a perpendicular electrode geometry was realized. The in situ experiment showed a distinct response of the core-shell structure as a function of electric field. The irreversible reorientation of (001)-domain walls within the core was monitored, whereas the shell featured reversible changes in contrast.

[1] X. Tan, H. He, J.-K. Shang, J. Mater. Res, 20, 7,1641 (2005).

[2] M. Acosta, M. C. Scherrer, Wook Jo, L. A. Schmitt, M. Deluca, H.-J. Kleebe, J. Rödel, W. Donner, J. Am. Ceram. Soc., submitted (2014).

Acknowledgements: Financial support by the Deutsche Forschungsgemeinschaft, Sonderforschungsbereich 595 is gratefully acknowledged